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FORM PTO 1449 (modified) OCT 2 5 2007			DOCKET NO. 03500.017977.	APPLICATION NO.	LICATION NO. 10/809,483		
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE SOLICANT  LIST OF REFERENCES CITED BY APPLICANT MASAYA ASAO, et al.  (Use several sheets if necessary)							
			FILING DATE  March 26, 20		GROUP 1751		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
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FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
B. D. Cullity, "Elements of X-RAY DIFFRACTION", 2 <sup>nd</sup> Ed., Addison-Wesley Publishing Company, Inc., pp. 100-103.							
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EXAMINER			DATE CONSIDERED	DATE CONSIDERED			

Form #61

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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